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(57) Abstract :
 A deep learning-enabled bias detection and correction platform (101) is disclosed, comprising a Bias Detector Module (103) for real-time bias identification, a Bias Correction Module (104) for dataset rebalancing using GANs, and a Bias Explanation Engine (105) for feature interpretability. Integration APIs (106) enable seamless connection to data pipelines (102), with optional Reinforcement Learning Agent (109) for adaptive threshold tuning. The platform ensures fairness, enhances transparency, and minimizes bias in machine learning data streams.

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